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Application No.	<u>101014,405</u>	Prepared by	<u>NH</u>	Tracking Number	<u>05926136</u>
Examiner-GAU	<u>Whitmore - 2812</u>	Date	<u>4-27-4</u>	Week Date	<u>0329/04</u>
		No. of queries	( <u>1</u> )	IFW	

<b>JACKET</b>			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

<b>SPECIFICATION</b>	<b>MESSAGE</b>	
	<u>PTO-1449: Please either initial or line through citations. Copy provided for reference.</u>	
<b>CLAIMS</b>	<b>RESPONSE</b>	
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Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DKT. NO. 501.33873VC4	SERIAL NO.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (Use several sheets if necessary)		APPLICANT KAWAGOE, et al.		FILING DATE December 14, 2001
		FILING DATE	GROUP	

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## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	4,835,740	5-89	Sato			
AB	5,290,714	3-94	Onozawa			
AC	4,761,384	8-88	Neppl			
AD	5,156,990	10-92	Mitchell			
AE	6,043,114	3-00	Kawagoe			
AF	4,564,416	1-86	Homma, et al.			
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AH	5,237,188	8-93	Iwai, et al.			
AI	5,396,093	3-95	Lu			
AJ	5,508,540	4-96	Ikeda, et al.			
AK	5,508,549	4-96	Watanabe, et al.			
AL	3,974,003	8-76	Zirinsky, et al.			

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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation /Abstract	
						Yes	No
AM	0373723	6-20-90	Europe				
AN	0550021	7-85	Europe				
AO	60132358	7-85	Japan				
AP	58218159	12-83	Japan				
AQ	63157477	6-88	Japan				
AR	61002356	1-86	Japan				
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	Wolf, S., "Silicon Processing for the VLSI Era Vol. 1", ppg. 64-65.
AV	Ghandhi, S., "VLSI Fabrication Principles Silicon and Gallium Arsenide", ppg. 735-738.
AW	Yamaguchi, et al., "Process integration and device performance of a submicrometer BiCMOS with 16-GHz f(t) double Poly-Bipolar devices", IEEE Transactions on Electron Devices, Vol. 36, No. 5, ppg. 890-896.
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Examiner	Date Considered
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AB	4,525,920	7-85	Jacobs, et al.			
AC	4,717,686	1-88	Jacobs, et al.			
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AE	5,296,047	3-22-94	Fellner			
AF	4,477,310	10-84	Park, et al.			
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AK	4,662,082	11-86	Dyson, et al.			
AL						

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**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

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